### **EPC2024 – Enhancement Mode Power Transistor**

 $V_{DS}$ , 40 V $R_{DS(on)}\,,\,\,1.5\,m\Omega$ I<sub>D</sub>, 90 A









Gallium Nitride's exceptionally high electron mobility and low temperature coefficient allows very low R<sub>DS(on)</sub>, while its lateral device structure and majority carrier diode provide exceptionally low Q<sub>G</sub> and zero Q<sub>RR</sub>. The end result is a device that can handle tasks where very high switching frequency, and low on-time are beneficial as well as those where on-state losses dominate.

Maximum Ratings								
	PARAMETER VALUE							
\ \ \	Drain-to-Source Voltage (Continuous)	40	V					
V <sub>DS</sub>	Drain-to-Source Voltage (up to 10,000 5 ms pulses at 150°C)	48	V					
	Continuous ( $T_A = 25$ °C, $R_{\theta JA} = 6$ °C/W)	90	۸					
I <sub>D</sub>	Pulsed (25°C, T <sub>PULSE</sub> = 300 μs)	560	А					
V	Gate-to-Source Voltage	6						
$V_{GS}$	Gate-to-Source Voltage	-4	V					
TJ	Operating Temperature -40 to 150							
T <sub>STG</sub>	Storage Temperature	-40 to 150	- ℃					

Thermal Characteristics							
	PARAMETER	ТҮР	UNIT				
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case	0.4					
$R_{\theta JB}$	Thermal Resistance, Junction-to-Board	1.1	°C/W				
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient (Note 1)	42					

Note 1:  $R_{\theta JA}$  is determined with the device mounted on one square inch of copper pad, single layer 2 oz copper on FR4 board. See https://epc-co.com/epc/documents/product-training/Appnote\_Thermal\_Performance\_of\_eGaN\_FETs.pdf for details.

1	1	n	n	n	1	n	1	1	M	1	1	n	1	
U	U	U	U	U	V	U	U	U	U	U	U	Ų	U	U
n	n	n	n	n	n	n	n	n	n	n	n	n	n	n
U	U	U	U	U	U	U	U	U	U	U	U	U	U	

EPC2024 eGaN® FETs are supplied only in passivated die form with solder bumps. Die Size: 6.05 mm x 2.3 mm

- High Speed DC-DC Conversion
- · Motor Drive
- · Industrial Automation
- Synchronous Rectification
- · Inrush Protection
- · Point-of-Load (POL) Converters



	Static Characteristics ( $T_J = 25^{\circ}$ C unless otherwise stated)								
	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT			
$BV_{DSS}$	Drain-to-Source Voltage	$V_{GS} = 0 \text{ V, I}_{D} = 1.1 \text{ mA}$	40			V			
I <sub>DSS</sub>	Drain-Source Leakage	$V_{GS} = 0 \text{ V}, V_{DS} = 32 \text{ V}$		0.1	0.9	mA			
	Gate-to-Source Forward Leakage	$V_{GS} = 5 V$		1	9	mA			
I <sub>GSS</sub>	Gate-to-Source Reverse Leakage	$V_{GS} = -4 V$		0.1	0.9	mA			
$V_{GS(TH)}$	Gate Threshold Voltage	$V_{DS} = V_{GS}$ , $I_{D} = 19 \text{ mA}$	0.8	1.4	2.5	V			
R <sub>DS(on)</sub>	Drain-Source On Resistance	$V_{GS} = 5 \text{ V}, I_D = 37 \text{ A}$		1.2	1.5	mΩ			
$V_{SD}$	Source-Drain Forward Voltage	$I_S = 0.5 \text{ A, } V_{GS} = 0 \text{ V}$		1.8		V			

All measurements were done with substrate connected to source.

Dynamic Characteristics ( $T_J = 25^{\circ}$ C unless otherwise stated)							
	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT	
C <sub>ISS</sub>	Input Capacitance			1920	2300		
Coss	Output Capacitance	$V_{DS} = 20 \text{ V}, V_{GS} = 0 \text{ V}$		1620	2430		
C <sub>RSS</sub>	Reverse Transfer Capacitance			29		рF	
C <sub>OSS(ER)</sub>	Effective Output Capacitance, Energy Related (Note 2)	V 0. 20VV 0V		2050			
C <sub>OSS(TR)</sub>	Effective Output Capacitance, Time Related (Note 3)	$V_{DS} = 0$ to 20 V, $V_{GS} = 0$ V		2240			
$R_{G}$	Gate Resistance			0.3		Ω	
Q <sub>G</sub>	Total Gate Charge	$V_{DS} = 20 \text{ V}, V_{GS} = 5 \text{ V}, I_D = 37 \text{ A}$		18	24		
Q <sub>GS</sub>	Gate-to-Source Charge			5.1			
$Q_{GD}$	Gate-to-Drain Charge	$V_{DS} = 20 \text{ V}, I_D = 37 \text{ A}$		2.4		nC	
Q <sub>G(TH)</sub>	Gate Charge at Threshold			3.8			
Qoss	Output Charge	$V_{DS} = 20 \text{ V}, V_{GS} = 0 \text{ V}$		45	68	1	
Q <sub>RR</sub>	Source-Drain Recovery Charge			0		1	

All measurements were done with substrate connected to source.

Note 2:  $C_{OSS(ER)}$  is a fixed capacitance that gives the same stored energy as  $C_{OSS}$  while  $V_{DS}$  is rising from 0 to 50% BV<sub>DSS</sub>. Note 3:  $C_{OSS(TR)}$  is a fixed capacitance that gives the same charging time as  $C_{OSS}$  while  $V_{DS}$  is rising from 0 to 50% BV<sub>DSS</sub>.

Figure 1: Typical Output Characteristics at 25°C

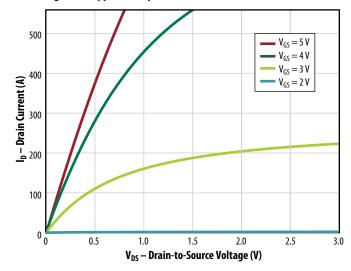


Figure 3: R<sub>DS(on)</sub> vs. V<sub>GS</sub> for Various Drain Currents

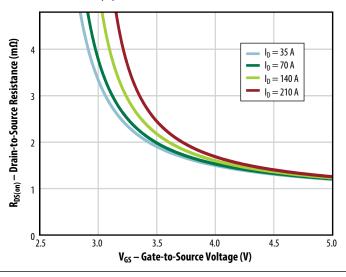


Figure 2: Transfer Characteristics

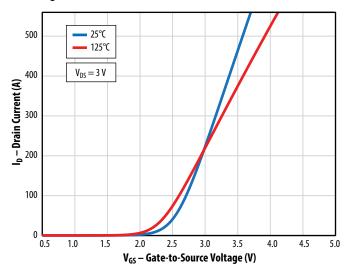


Figure 4:  $R_{DS(on)}$  vs.  $V_{GS}$  for Various Temperatures

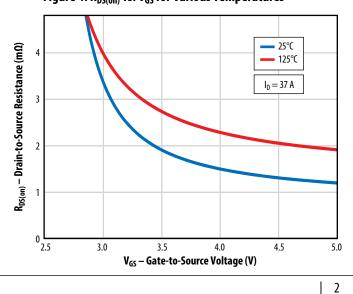


Figure 5a: Capacitance (Linear Scale)

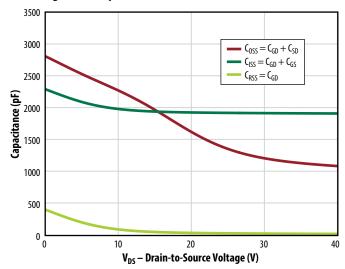


Figure 5b: Capacitance (Log Scale)

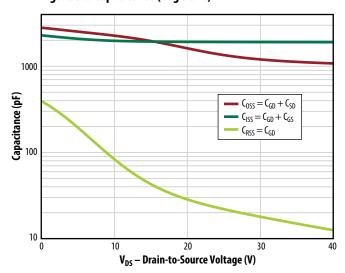


Figure 6: Gate Charge

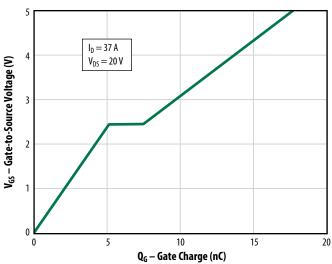


Figure 7: Reverse Drain-Source Characteristics

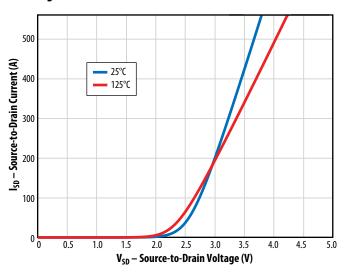


Figure 8: Normalized On-State Resistance vs. Temperature

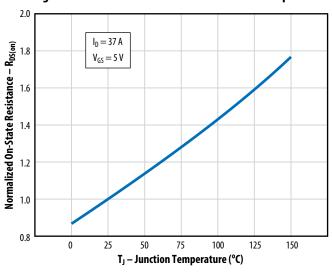


Figure 9: Normalized Threshold Voltage vs. Temperature

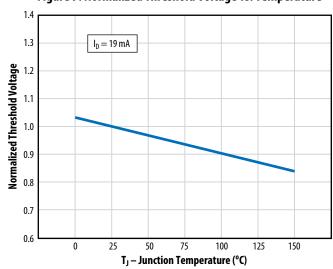
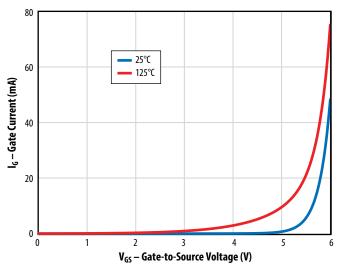
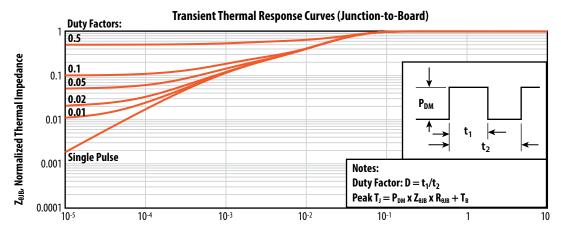


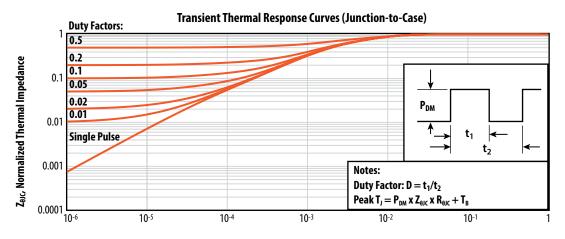
Figure 10: Gate Leakage Current



**Figure 11: Transient Thermal Response Curves** 

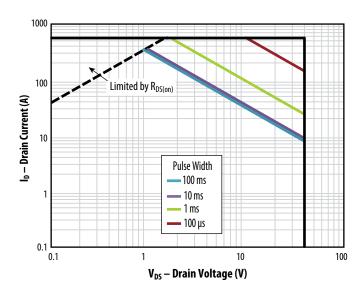


t<sub>1</sub>, Rectangular Pulse Duration, seconds

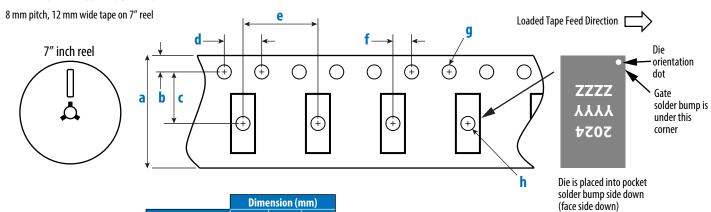


 $t_1, Rectangular \, Pulse \, Duration, seconds$ 

Figure 12: Safe Operating Area



#### **TAPE AND REEL CONFIGURATION**

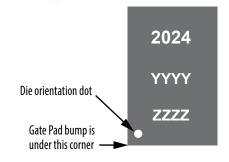


	Difficultion (IIIII)			
EPC2024 (Note 1)	Target	MIN	MAX	
a	12.00	11.90	12.30	
b	1.75	1.65	1.85	
c (Note 2)	5.50	5.45	5.55	
d	4.00	3.90	4.10	
е	8.00	7.90	8.10	
f (Note 2)	2.00	1.95	2.05	
g	1.50	1.50	1.60	
h	1.50	1.50	1.75	

Note 1: MSL 1 (moisture sensitivity level 1) classified according to IPC/ JEDEC industry standard.

Note 2: Pocket position is relative to the sprocket hole measured as true position of the pocket, not the pocket hole.

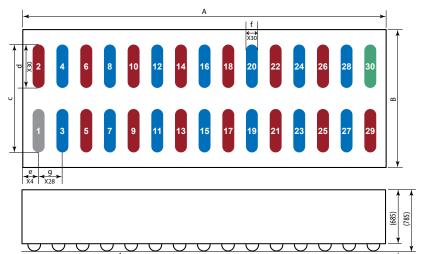
#### **DIE MARKINGS**



Dout	Laser Markings						
Part Number	Part # Marking Line 1	Lot_Date Code Marking Line 2	Lot_Date Code Marking Line 3				
EPC2024	2024	YYYY	ZZZZ				

#### **DIE OUTLINE**

**Solder Bump View** 



	Micrometers						
DIM	MIN	Nominal	MAX				
A	6020	6050	6080				
В	2270	2300	2330				
c	2047	2050	2053				
d	717	720	723				
e	210	225	240				
f	195	200	205				
g	400	400	400				

Pad 1 is Gate;

Pads 2,5,6,9,10,13,14,17,18,21,22, 25,26,29 are Source;

Pads 3, 4, 7, 8, 11, 12, 15, 16, 19, 20, 23, 24, 27, 28 are Drain;

Pad 30 is Substrate.\*

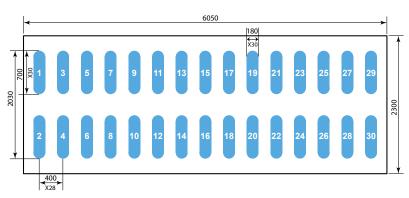
\*Substrate pin should be connected to Source

# RECOMMENDED LAND PATTERN

Seating plane

(units in  $\mu$ m)

Side View



Land pattern is solder mask defined Solder mask opening is 180 µm It is recommended to have on-Cu trace PCB vias

Pad 1 is Gate;

Pads 2, 5, 6, 9,10,13,14, 17, 18, 21, 22,

25, 26, 29 are Source;

Pads 3, 4, 7, 8, 11, 12, 15, 16, 19, 20, 23,

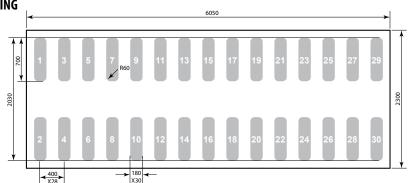
24, 27, 28 are Drain;

Pad 30 is Substrate.\*

\*Substrate pin should be connected to Source

## RECOMMENDED STENCIL DRAWING

(units in µm)



Recommended stencil should be 4 mil (100  $\mu$ m) thick, must be laser cut, openings per drawing.

Intended for use with SAC305 Type 4 solder, reference 88.5% metals content.

Additional assembly resources available at https://epc-co.com/epc/DesignSupport/ AssemblyBasics.aspx

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Information subject to change without notice.
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